

United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE
United States Patent and Trademark Office
Address: COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, Virginia 22313-1450
www.uspto.gov

APPLICATION NO). F	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/731,355	10/731,355 12/09/2003		Jose Arno	ATMI 567-Div-Con-3	3545
25559	7590	02/21/2006		EXAMINER	
ATMI, IN		T.	STEVENSON, ANDRE C		
7 COMMERCE DRIVE DANBURY, CT 06810			ART UNIT	PAPER NUMBER	
				2812	
				DATE MAILED: 02/21/2006	; .

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)				
Office Action Summary		10/731,355	ARNO, JOSE				
		Examiner	Art Unit				
		Andre' C. Stevenson	2812				
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply							
A SH WHIC - Exter after - If NO - Failu Any	ORTENED STATUTORY PERIOD FOR REPLY CHEVER IS LONGER, FROM THE MAILING DANSIONS of time may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. In period for reply is specified above, the maximum statutory period were to reply within the set or extended period for reply will, by statute, reply received by the Office later than three months after the mailing and patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be timustill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	N. nely filed the mailing date of this communication. D (35 U.S.C. § 133).				
Status							
2a)⊠	Responsive to communication(s) filed on <u>20 Ja</u> This action is FINAL . 2b) This Since this application is in condition for allowar closed in accordance with the practice under E	action is non-final. nce except for formal matters, pro					
Disposition of Claims							
5)□ 6)⊠ 7)⊠	Claim(s) <u>1-5</u> is/are pending in the application. 4a) Of the above claim(s) is/are withdraw Claim(s) is/are allowed. Claim(s) <u>1-5</u> is/are rejected. Claim(s) <u>6-10</u> is/are objected to. Claim(s) are subject to restriction and/or						
Applicati	on Papers						
10)🖾	The specification is objected to by the Examine The drawing(s) filed on <u>09 December 2003</u> is/an Applicant may not request that any objection to the Replacement drawing sheet(s) including the correction The oath or declaration is objected to by the Ex	re: a) \square accepted or b) \square objected or by accepted or by accepted in abeyance. See ion is required if the drawing(s) is object.	e 37 CFR 1.85(a). lected to. See 37 CFR 1.121(d).				
Priority u	ınder 35 U.S.C. § 119						
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 							
Attachmen	t(s)						
1) Notice 2) Notice 3) Inform	te of References Cited (PTO-892) te of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) r No(s)/Mail Date 01/20/06.	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:					

Detailed Action

Information Disclosure Statement

The information disclosure statement (IDS) submitted on January 20, 2006 was filed after the mailing date the first action on the merits, but before the close of prosecution. The submission is in compliance with the provisions of 37 CFR 1.97. Accordingly, the information disclosure statement is being considered by the examiner.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims #1-5 are rejected under 35 U.S.C. 103(a) as being unpatentable over Sorensen et al. (U.S. Pat. No. 5,782,974 B2, Pat. Date 07/21/98, File 05/16/96), in view of Tanaka (U.S. Pat. No. 5,594,248, Pat. Date 01/14/97, File 03/12/96).

Sorensen substantially shows, in figures 1-3 and corresponding text, in a similar method for measuring temperatures, with respect to claim #1, a semiconductor process system adapted for processing of or with a material therein, said system comprising; a sampling region for the material (column #3, line 34-51); an infrared radiation source constructed and arranged to transmit infrared radiation through the sampling region (item #26) (column #4, line 46-67); a thermopile detector (item #18) constructed and arranged to receive infrared radiation after the

Art Unit: 2812

transmission thereof through the sampling region and to responsively generate an output signal correlative of said material (column #5, line 46-67; column #6, line 1-5; column #7, line 1-12); and process control means (item #19) arranged to receive the output of the thermopile detector and to responsively control one or more process conditions in and/or affecting the semiconductor process system (column #4, line 40-45; column #7, line 13-21). Pertaining to claim #2, Won shows a method wherein the material comprises a solid (item #10) (column #4, line 13-33). Pertaining to claim #3, Sorensen shows a method wherein the material comprises a fluid (column #8, line 8-24). Pertaining to claim #4, Sorensen shows a method wherein the material comprises a liquid (column #8, line 8-24). The Examiner notes that Sorensen does not mention explicitly that the material, stated in claims #3 and 4, comprise of a fluid or a liquid. However, the Examiner notes that Sorensen shows, in column 4 lines 21-33, that molecular gases are excited in the plasma region (16) and subsequently these gases, or portions of the gases, deposit on the surface of the deposition substrate (10), to form thin film layers on the substrate. Sorensen also shows that the susceptor is maintained at an appropriate temperature for deposition to occur. Thus, the deposition gases, as the substrate decreases in temperature, go through a triple point phase;

- 1) Gas; actual deployment of the material.
- 2) Liquid; as the gases attach to the substrate.
- 3) Solid; as the substrate cools and the deposited material becomes a solid.

The Examiner takes the position that through this process, the susceptor, which is monitored and controlled by the thermopile detector and the computer, operates on a material that is a gas, a liquid, and then a solid. For this reason, the Examiner takes the position that the

claimed invention, as it is now written, is taught by Sorensen. *Pertaining to claim #5*, Sorensen shows a method wherein the material comprises a gas (column #8, line 8-24).

Sorensen fails to show, with respect to claim #1, the transmission of the infrared beam through the sampling region.

Tanaka teaches, in a similar method involving an infrared imaging device that has a plurality of detectors, with respect to claim #1, the transmission of the infrared beam through the sampling region (column #5, line 53-67; column #6, line 1-29).

It would have been obvious to one having ordinary skill in the art at the time the invention was made, with respect to claim #1, to include the step having a transmission of a infrared beam through a sampling region, into the method of Sorensen, as taught by Tanaka, with the motivation that having the infrared imaging system, when used to recognizes a defective pixel detection mode in response to a predetermined signal supplied from an external source, produces a normal image signal that is free of defective image data from defective pixels

Allowable Subject Matter

Claims #6 through 10 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Claim #6, upon further updated search.

✓ Radiation source comprises an infrared radiation lamp.

Claim #7, upon further updated search.

✓ Infrared radiation lamp generates said infrared radiation in a wavelength in the range of from about 2 to about 4.6 μm.

Claim #8, upon further updated search.

✓ Radiation source further comprises mirrors adapted to focus said infrared radiation beam.

Claim #9, upon further updated search.

✓ Mirrors are adapted to multipass said infrared radiation beam.

Claim #10, upon further updated search.

✓ Infrared radiation lamp generates said infrared radiation in a wavelength in the range of from about 2 to about 4.6 μm.

Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37

Art Unit: 2812

CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure; Tanaka (U.S. Pat. No. 5,594,248), Keenan (U.S. Pat. No. 5,367,167), Pompei et al. (U.S. Pat. No. 6,045,257), Chavan et al. (U.S. Pat. No. 6,828,172 B2), Sato et al. (U.S. Pub. No. 2003/0111605), Chavan et al. (U.S. Pub. No. 2003/0148620 A1), Mori et al. (U.S. Pat. No. 5,404,125), Irani et al. (U.S. Pat. No. 4,527,896).

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Andre' Stevenson whose telephone number is (571) 272 1683. The examiner can normally be reached on Monday through Friday from 7:30 am to 4:30 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael S. Lebentritt, can be reached on (571) 272 1873. The fax phone number for the organization where this application or proceeding is assigned is (703) 308 7724.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308 0956. Also, the proceeding numbers can be used to fax information through the Right Fax system;

(703) 872-9306

Andre' Stevenson

02/14/06

MICHAEL LEBENTRITT
SUPERVISORY PATENT EXAMINER